

Notice of References Cited	Application/Control No. 10/814,127		Applicant(s)/Patent Under Reexamination KANG ET AL.	
	Examiner Dipakkumar Gandhi		Art Unit 2117	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-6,574,280 B1	06-2003	Liau et al.	375/242
*	C	US-5,612,963	03-1997	Koenemann et al.	714/739
	D	US-			
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	K	US-			
	L	US-			
	M	US-			

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NON-PATENT DOCUMENTS

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	V	Chen et al., Efficient BIST TPG Design and Test Set Compaction via Input Reduction, IEEE Transactions on Computer-aided Design of Integrated Circuits and Systems, Vol. 17, No. 8, August 1998, Pages 692-705.			
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.